

## AMENDMENTS TO THE CLAIMS

The following listing of claims will replace all prior versions, and listings, of claims in the application:

### Listing of Claims:

1. (Currently Amended) An apparatus for managing a liquid crystal substrate, comprising:

a liquid crystal testing device operable to determine whether at least one of a panel and a substrate in the liquid crystal substrate has a defect, and acquire defect information indicative of at least the defect and whether the at least one of the panel and the substrate is defective;

a liquid crystal repair device operable to repair the defect based on the defect information, and acquire repair information indicative of a defect that is actually repaired; and

a data management section having a database for recording a adapted to record the defect information which is acquired from a the liquid crystal testing device, and an image information and a the repair information including a defect repaired information which are is acquired from a the liquid crystal repair device, wherein:

said data management section performing is operable to redetermine at least one of a reidentification of a the defect and a redetermination of whether the at least one of a the panel and a the substrate is defective, based on the defect information;

the image information and the repair information which are recorded in said database.

2. (Original) The liquid crystal substrate managing apparatus according to claim 1, wherein said data management section stores a recipe information for defining specifications of the substrate and panel in said database, said recipe information being edited freely.

3. (Original) The liquid crystal substrate managing apparatus according to claim 2, wherein said data management section edits the recipe information by exchange of information with a terminal connecting to the data management section.

4. (Currently Amended) A method for managing a liquid crystal substrate comprising:

determining whether at least one of a panel and a substrate in the liquid crystal substrate has a defect, and acquire defect information indicative of at least the defect and whether the at least one of the panel and the substrate is defective;

repairing the defect based on the defect information, and acquires repair information indicative of at least a position that is actually repaired;

recording, in a database, thea defect information which is acquired from a-the liquid crystal testing device, and an image information and athe repair information including a defect repaired information which areis acquired from athe liquid crystal repair device in a database; and

performing redetermining at least one of a reidentification of athe defect and a

~~redetermination of whether the~~ at least one of ~~the~~ panel and ~~the~~ substrate is ~~defective, based on the defect information, the image information and the repair information which are~~ recorded in the database.

5. (Original) The liquid crystal substrate managing method according to claim 4, further comprising:

recording a recipe information acquired from the liquid crystal testing device in the database, the recipe information defining specifications of the substrate and panel and being edited freely.

6. (New) The liquid crystal substrate managing apparatus according to claim 1, wherein:

    said liquid crystal repair device is operable to correct the defect information to generate corrected defect information when the defect indicated by the defect information is different from the defect indicated by the repair information; and

    said data management section is operable to update the defect information recorded in said database with the corrected defect information.

7. (New) The liquid crystal substrate managing apparatus according to claim 1, wherein:

    the repair information includes image information of a part of the at least one of the panel and the substrate that is actually repaired.

8. (New) The liquid crystal substrate managing apparatus according to claim

1, wherein:

    said data management section is operable to acquire trend information for defects of a plurality of lid crystal substrates, by applying statistical processing with respect to the defect information and the repair information recorded in the database.

9. (New) The method for managing a liquid crystal substrate as set forth in claim 4, further comprising:

    correcting the defect information to generate corrected defect information when the defect indicated by the defect information is different from the defect indicated by the repair information; and

    updating the defect information recorded in said database with the corrected defect information.

10. (New) The method for managing a liquid crystal substrate according to claim 4, wherein:

    the repair information includes image information of a part of the at least one of the panel and the substrate that is actually repaired.

11. (New) The method for managing a liquid crystal substrate according to claim 4, further comprising:

    acquiring trend information for defects of a plurality of liquid crystal substrates, by applying statistical processing with respect to the defect information and the repair information recorded in the database.